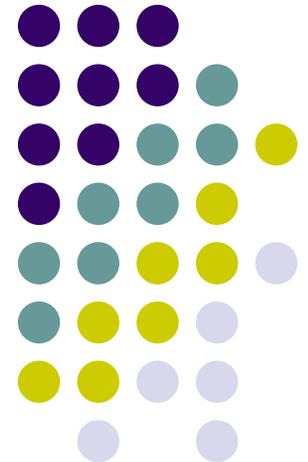


Integrated High Speed VCSELs for Bi-Directional Optical Interconnects

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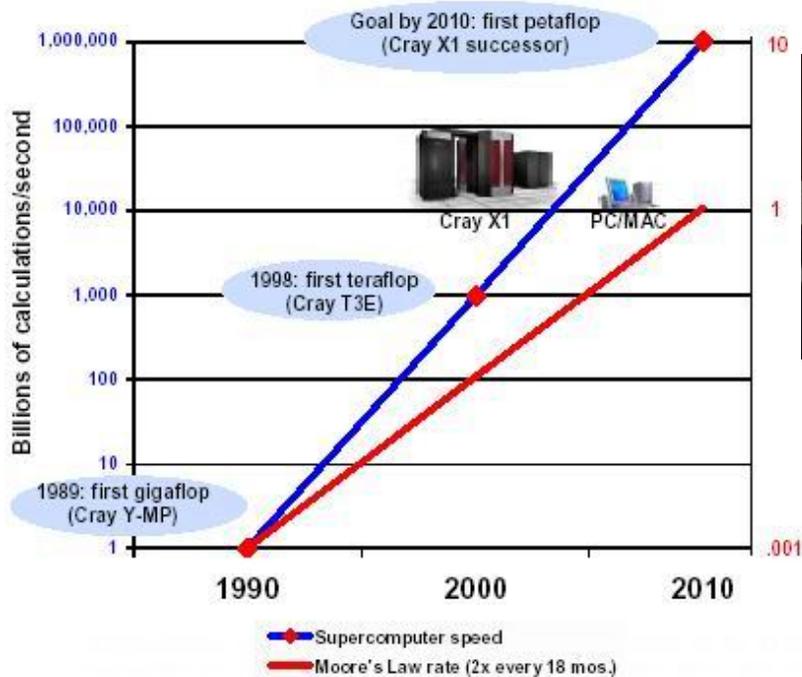


Outline

- Introduction
- Model description
- Structure optimization of VCSEL
- Conclusions



Computers: past, present and future



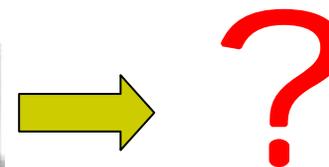
Cray1 1980s



Pocket PC 2000s



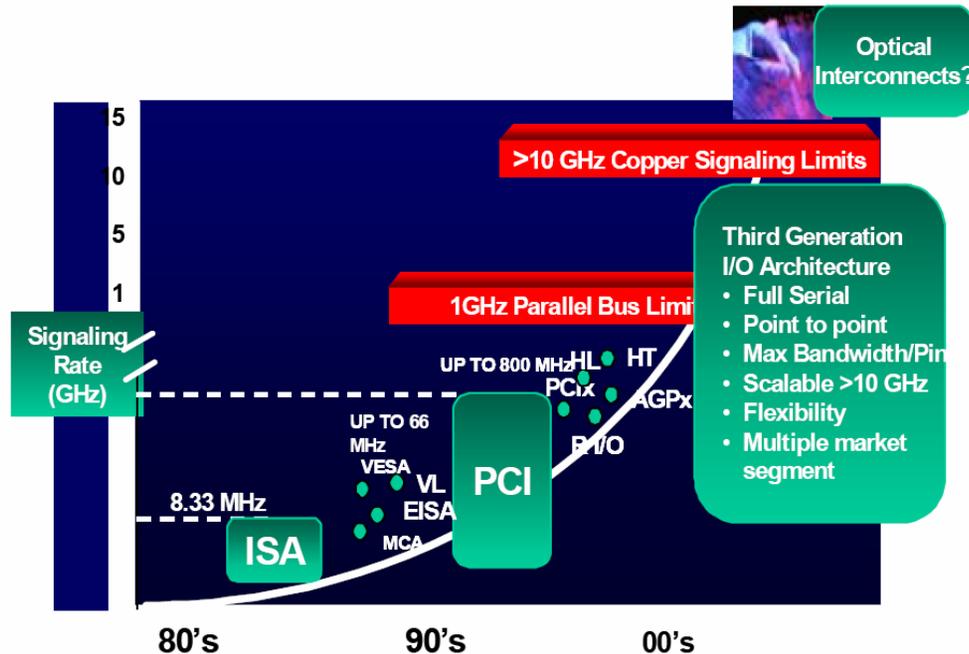
Cray X1 2000s



PC 2020s



Computer I/O architecture history and I/O roadmap



Beyond 10 GHz, copper interconnects, become bandwidth limited due to frequency-dependent losses such as the skin effect in the conductors and the dielectric loss from the substrate material.

We need the optoelectronic devices with

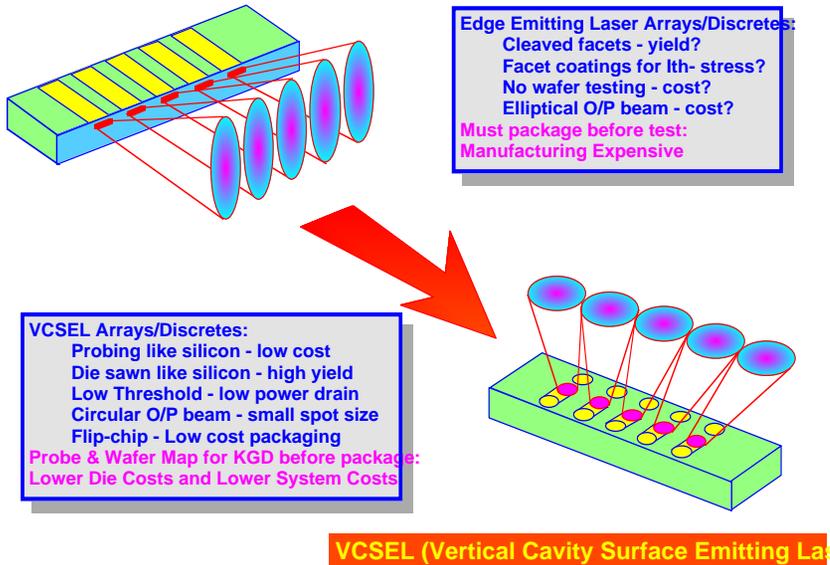
- good performance (high-modulation bandwidth, low power consumption, high efficiency)
- manufacturing advantages (amenable to high-volume production, wafer-level testing, and ease of integration).

E. Mohammed et.al, Intel Technology Journal, V.8 N.2, 2004, pp. 115-127



VCSELs over Edge Emitter lasers

VCSELs Vs EEs (Arrays)

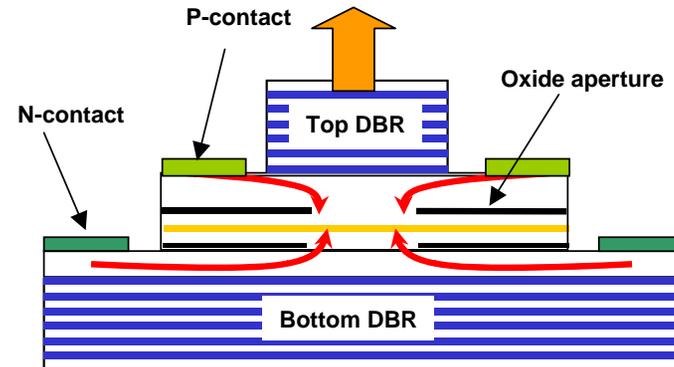
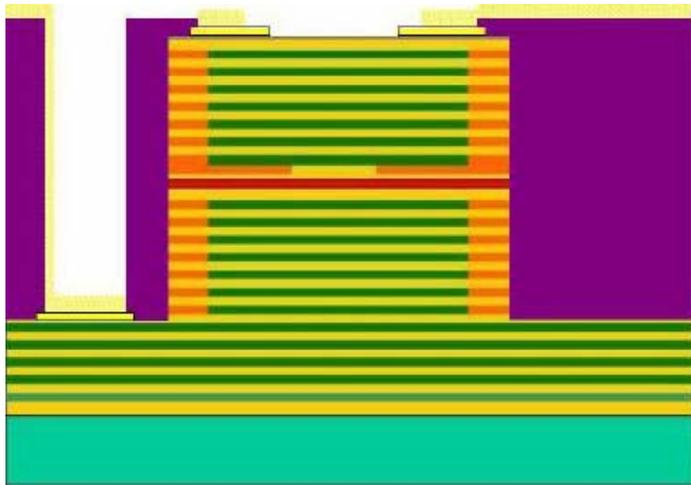


- VCSELs are characterized by:
- Low threshold Current.
- High power conversion efficiency.
- Less heating.
- Convenient operating wavelength.
- High speed of operation > 10 GHz.
- Surface normal light output.
- Circularly shaped, low NA output beams.
- Small size compared to other kinds of laser diodes.
- Very good potential for 2D arrays.
- Low cost wafer scale fabrication.

- Important space applications:
- High speed fiber optic networks.
- Free space optical communication.
- Optical interconnects.
- Optical storage systems.

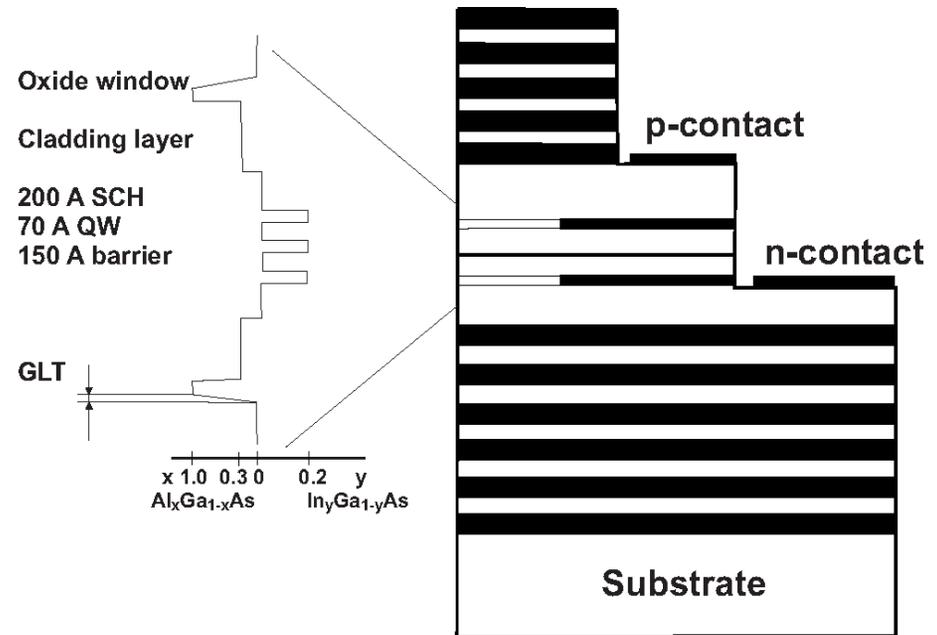
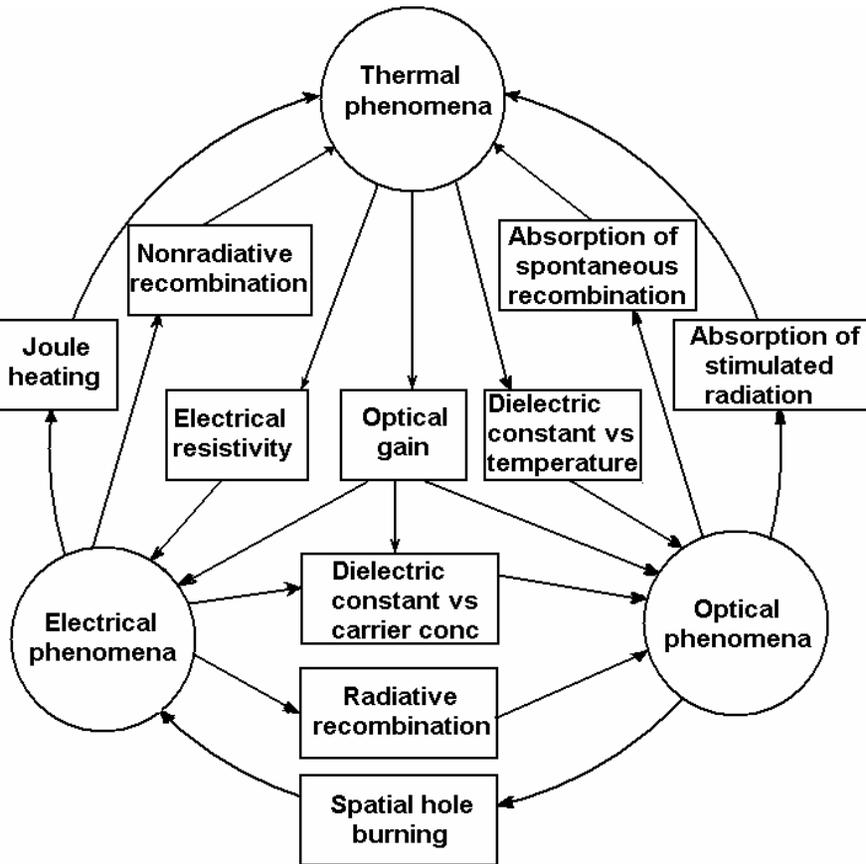
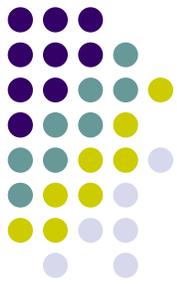


Intracavity contacted VCSEL array



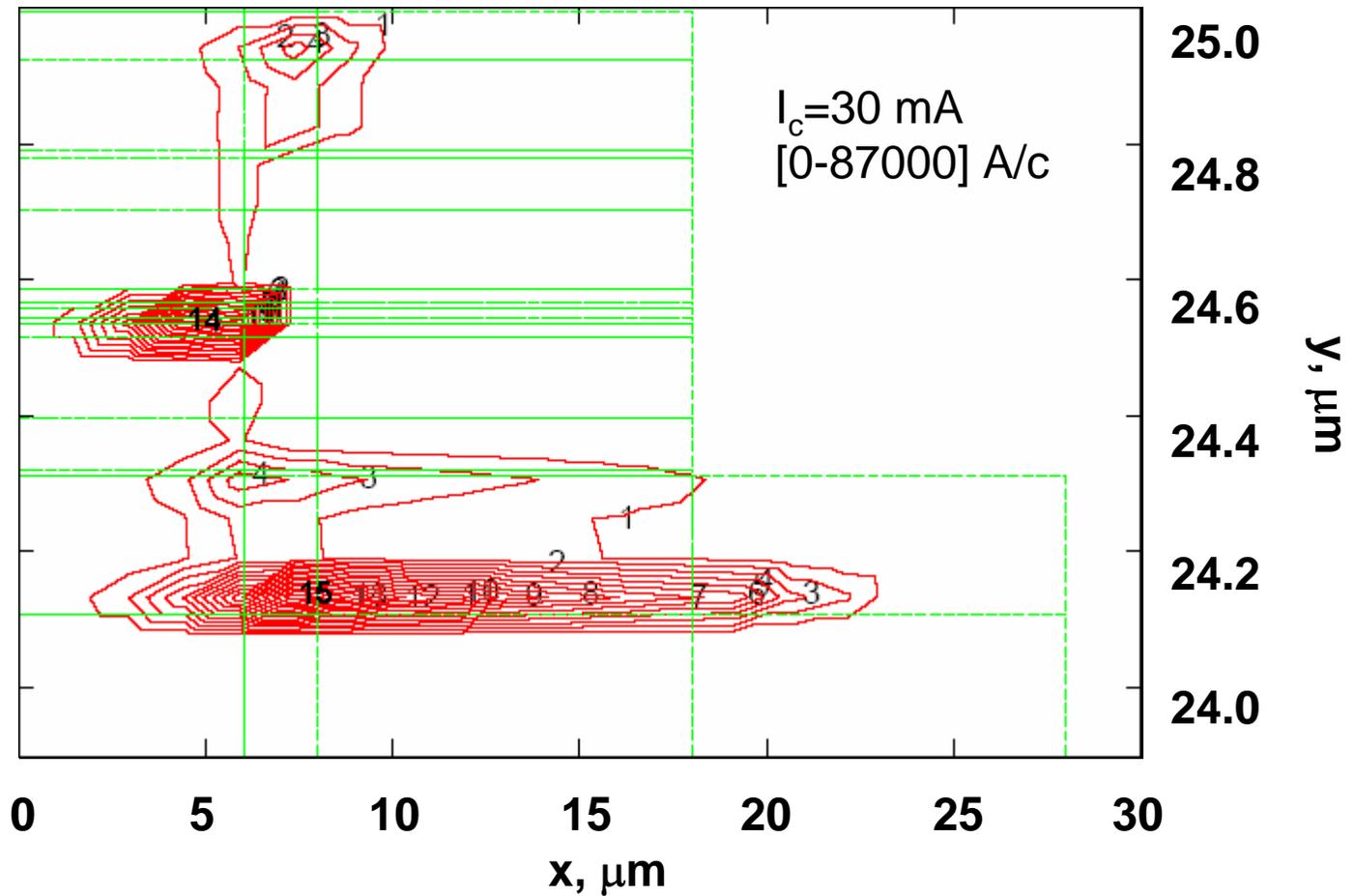
- + **Bypass the current flow through mirrors**
⇒ *lowers the series resistance*
- + **Use of undoped DBR mirror**
⇒ *reduce free carrier absorption*
⇒ *better reflectivity*
- + **Co-planar contact**
⇒ *suitable for flip-chip bonding*
- **Current crowding effect**

Interactions between physical processes in LD



PICS3D Crosslight program

Total current magnitude for different pumping currents



Thermal phenomena



Basic thermal equation

$$C_P \rho \frac{\partial T}{\partial t} = \nabla \cdot \kappa \nabla T + H$$

Heat sources

Material density

Thermal conductivity

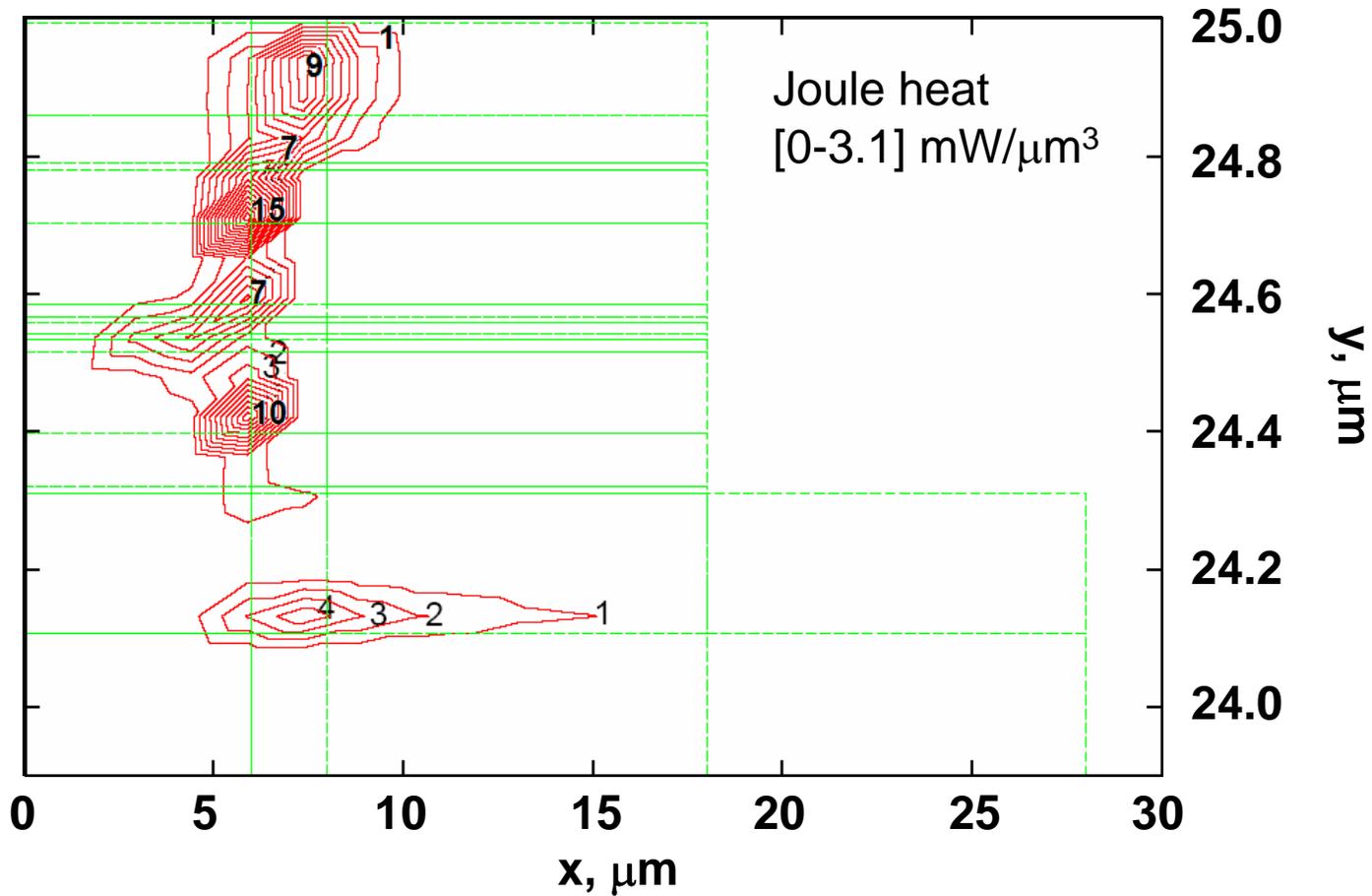
Heat coefficient

$$H = H_{Joule-dc} + H_{Joule-op} + H_{rec} + H_T + H_P$$

~17 % ~1 % 80 % 0.001 % ~2 %

Steady-state Electrical field Optical wave absorption on loss semiconductors Recombination heat Thomson heat Peltier heat

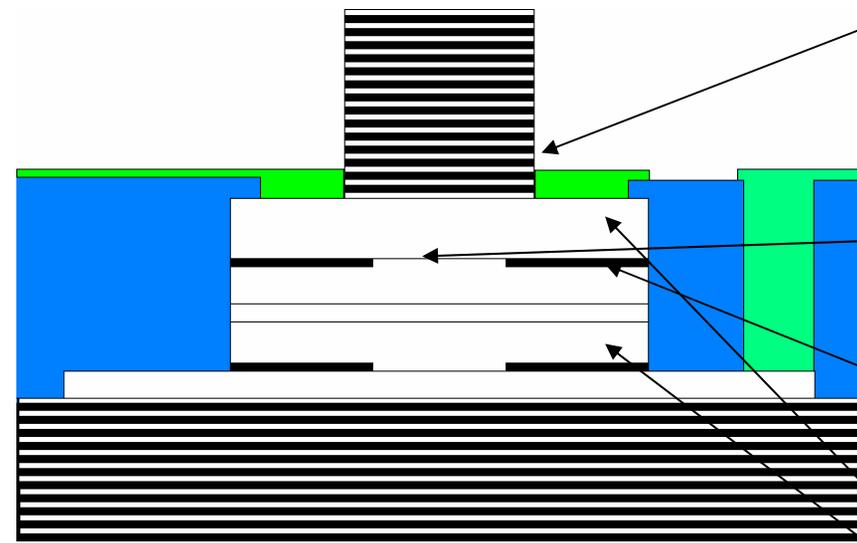
Heat sources in ICOC VCSEL





Structure optimization

$$R_{ot} = \frac{d_{top\ mirror}}{d_{oxide\ window}}$$



$R_{ot} \uparrow$ $R_{tot} \uparrow$ $f_{3dB} \downarrow$
 $R_{ot} \downarrow$ optic loss \uparrow $f_{3dB} \downarrow$

Graded layer thickness

$t_{gr} \downarrow$ $R_{tot} \uparrow$ $f_{3dB} \downarrow$
 $t_{gr} \uparrow$ $L_{pen} \uparrow$ $f_{3dB} \downarrow$

Oxide window diameter

$D_{ox} \downarrow$ $R_{tot} \uparrow$ $f_{3dB} \downarrow$
 $D_{ox} \uparrow$ $V_{act} \uparrow$ $f_{3dB} \downarrow$

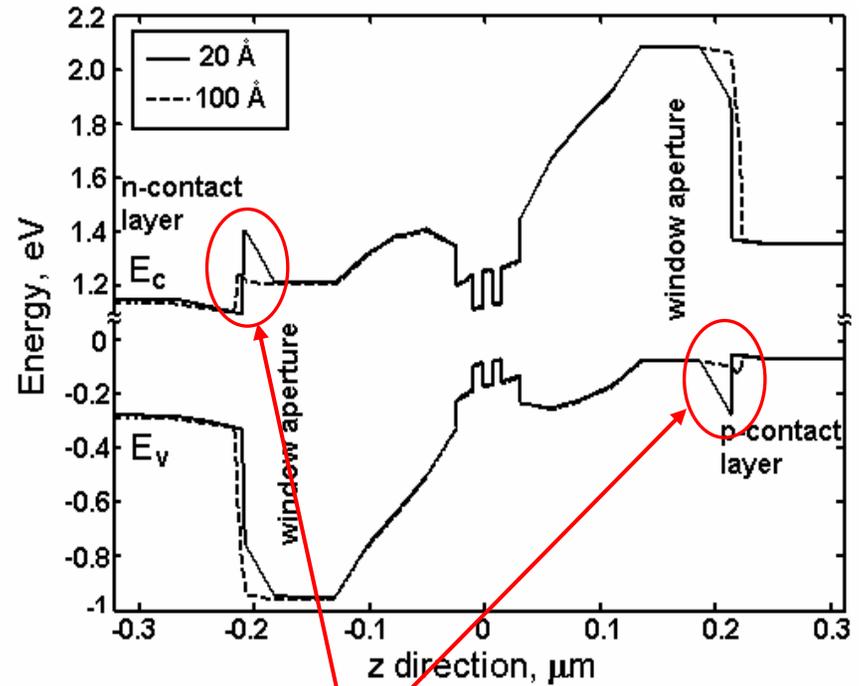
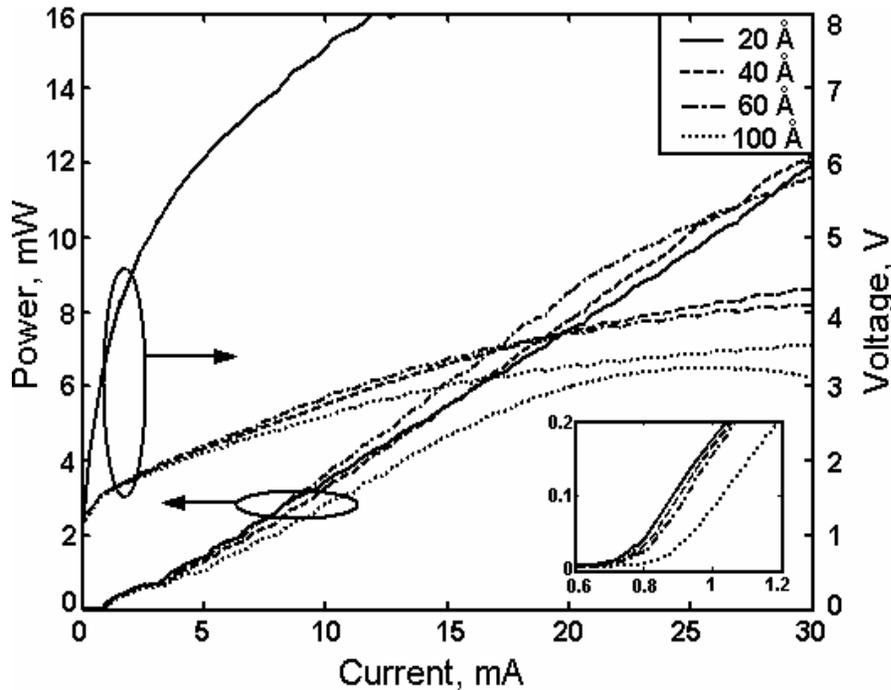
Contact layer thickness

$t_{cont} \downarrow$ $R_{tot} \uparrow$ $f_{3dB} \downarrow$
 $t_{cont} \uparrow$ $L_{pen} \uparrow$ $f_{3dB} \downarrow$

Graded layer thickness I



I-L and I-V characteristics and energy band diagram in the center of structure for different values of **graded layer thickness** (GLT)

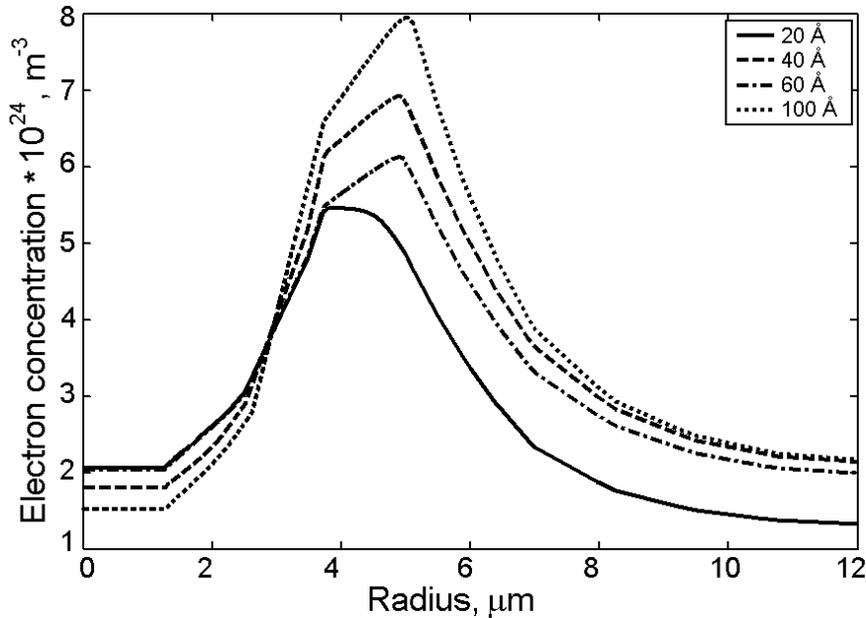


GLT \downarrow \rightarrow Energy "notches" \uparrow \rightarrow R_{tot} \uparrow

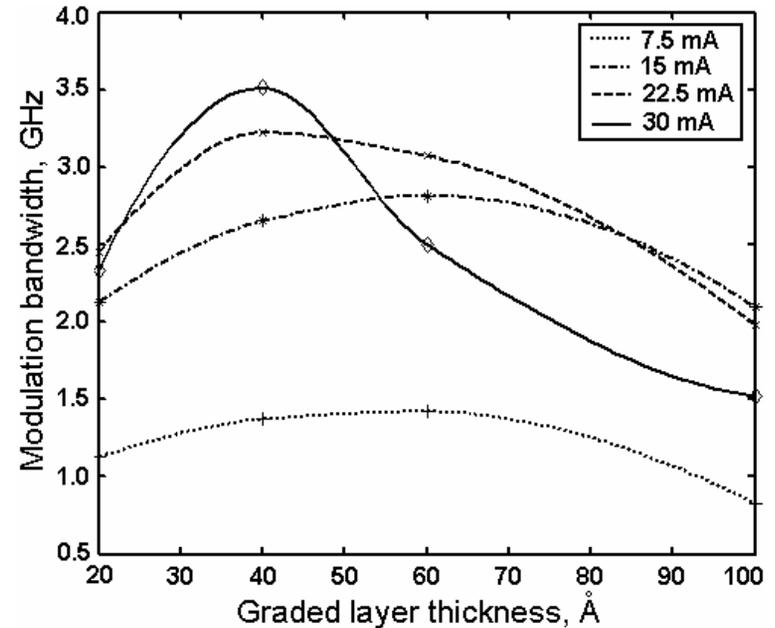
Graded layer thickness II



Radial distribution of electron concentration



f3dB bandwidth



GLT \uparrow \rightarrow current crowding effect \uparrow

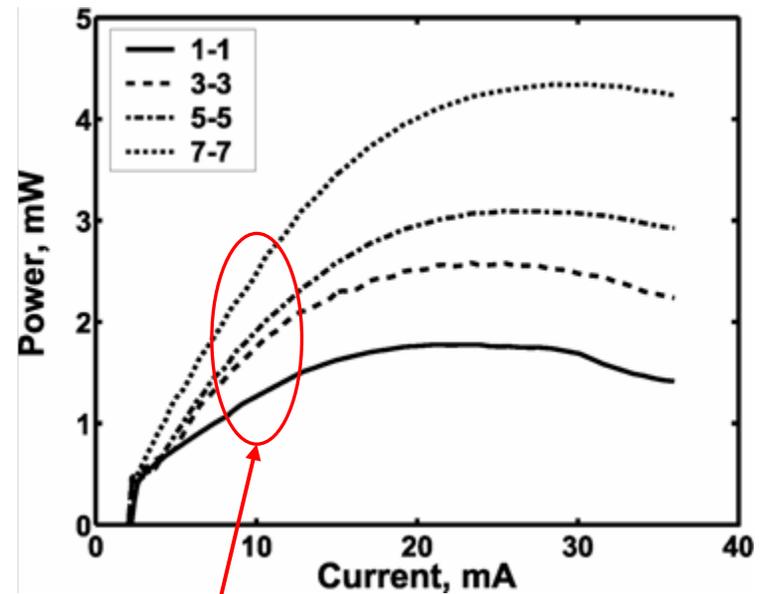
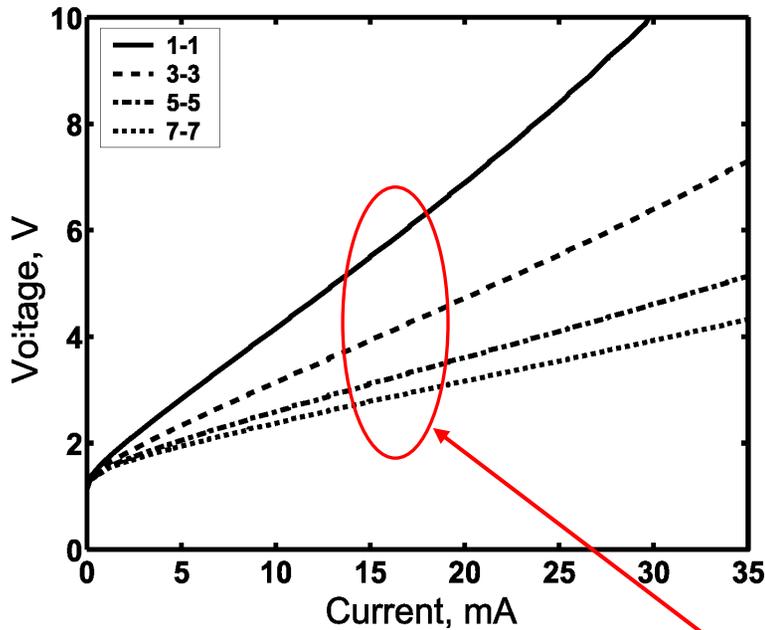
GLT \downarrow \rightarrow $R_{tot} \uparrow \rightarrow f_{3dB} \downarrow$
 GLT \uparrow \rightarrow $V_{eff} \uparrow$ + nonuniform current distribution $\rightarrow f_{3dB} \downarrow$

Contact layer thickness I



Contact layer is a part of DBR mirror $\rightarrow d=(2k+1)\lambda/4n$

a) V-I and b) L-I characteristics for different values of n - and p - contact layer thickness of $\lambda/4n$ (solid lines), $3\lambda/4n$ (dashed lines), $5\lambda/4n$ (dash-dotted lines) and $7\lambda/4n$ (dotted lines)

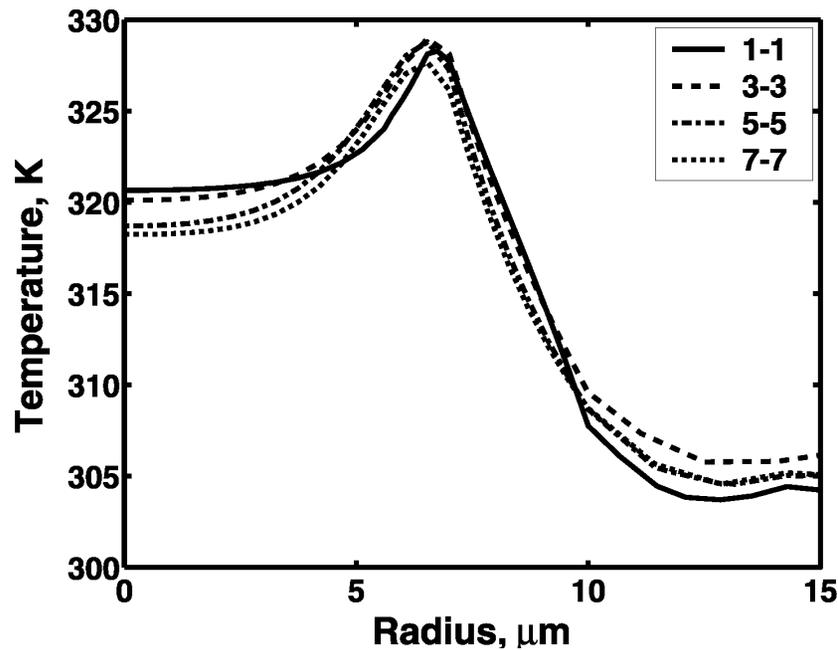


CLT \uparrow \rightarrow R_{layer} \downarrow \rightarrow R_{tot} \downarrow \rightarrow T_{active} \downarrow \rightarrow Gain \uparrow

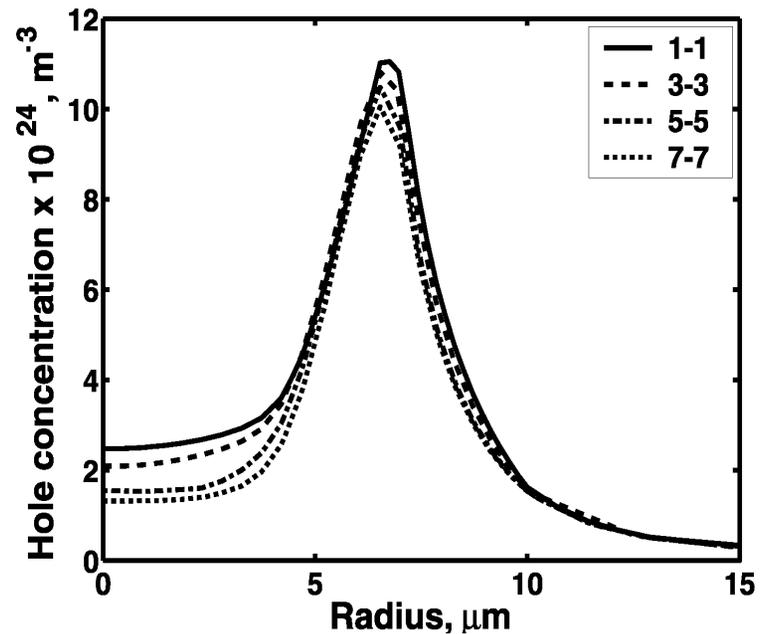
Contact layer thickness II



Radial distribution of the lattice temperature in active layer

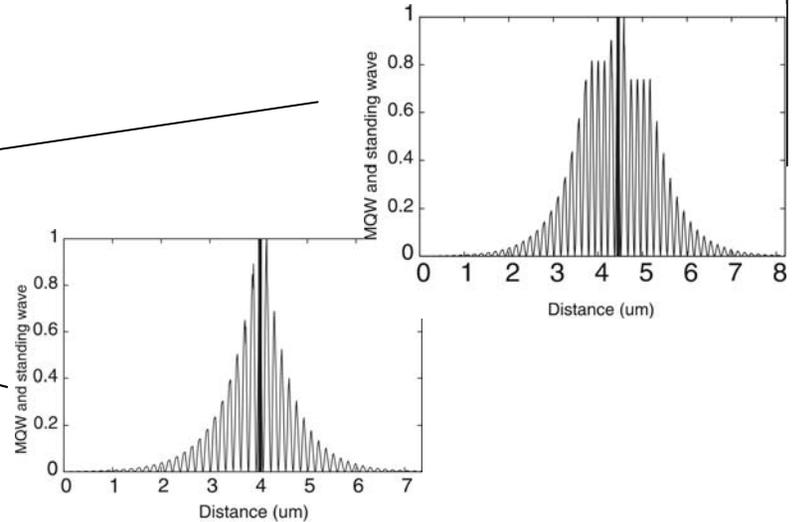
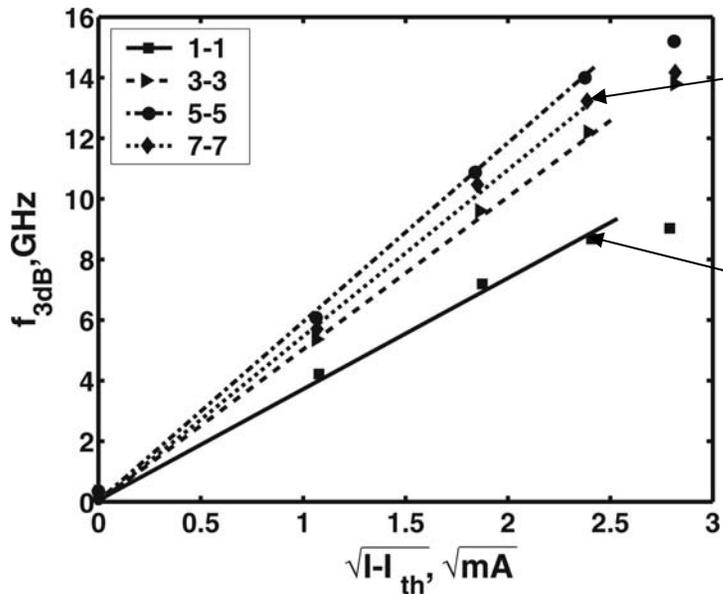


Radial distribution of the electron concentration



$CLT \uparrow \rightarrow R_{layer} \downarrow \rightarrow R_{tot} \downarrow \rightarrow T_{active} \downarrow \rightarrow Gain \uparrow$

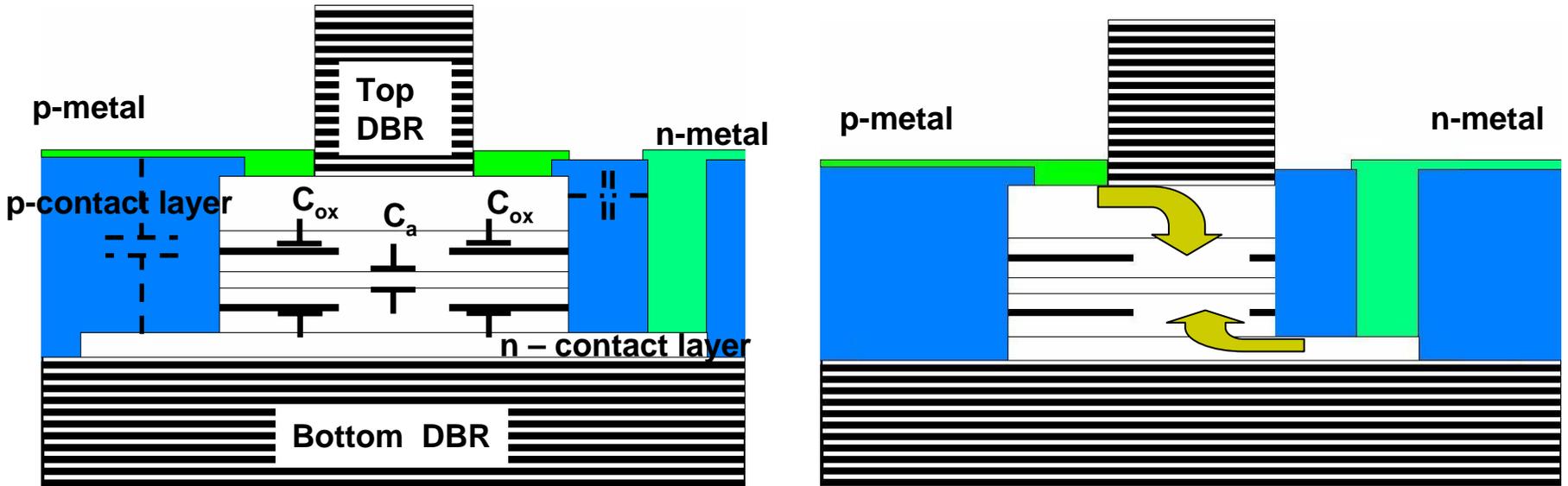
Contact layer thickness III



$$f_R = \frac{1}{2\pi} \sqrt{\eta_i \frac{\Gamma \xi v_g}{qV_{eff}} \frac{\partial g}{\partial N} (I - I_{th})}$$

Decreasing the CLT increases the differential resistance (see V-I characteristics).
 On the other hand, increasing the CLT changes the parameters as follows:
 increases the effective volume of resonator and decreases the gain enhancement factor due to increasing the penetration depths of DBR mirrors;
 reduces differential gain from the current crowding effect

Capacitance management

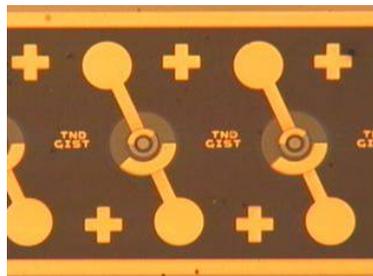
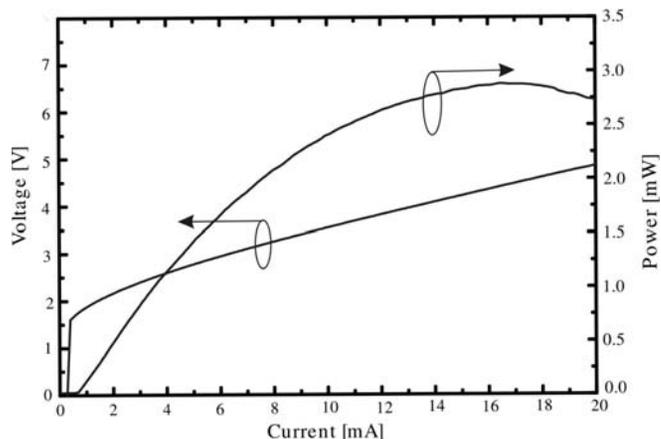


$C_{ox} \downarrow$ Counter-flowing paths for electrons and holes \longrightarrow asymmetrical contacts and suppress the conductivity

Experimental part

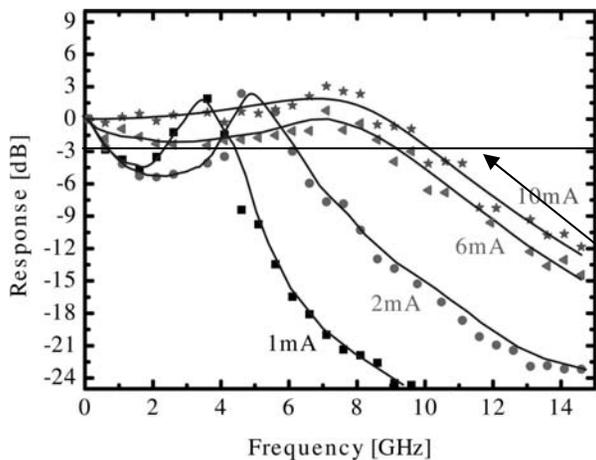


L-I-V characteristics



- Oxide aperture dia. : **5 μm**
- Threshold current : **$0.7 \pm 0.05 \text{ mA}$**
- Threshold voltage : **1.7 V**
- Slope efficiency : **$0.36 \pm 0.01 \text{ W/A @ } I=2\text{mA}$**
- Differential quantum efficiency:
 $28.4 \pm 0.7 \% @ I=2\text{mA}$
- Differential resistance : **$150 \Omega @ I=6\text{mA}$**

◆ small signal modulation



3dB bandwidth **10 GHz** at 10 mA



Conclusion

- we have analyzed the thermal, electrical, optical, and modulation properties of the 980 nm InGaAs ICOC VCSELs with different geometrical values
- devices with the optimal GLT of $40-60 \text{ \AA}$ have the highest output power and the widest modulation bandwidth due to compromise between the low resistance and more uniform radial carrier distribution in the active layer
- devices with the optimal CLT of $5\lambda/4n$ have the widest modulation bandwidth and the modulation conversion efficiency factor is approximately $5.92 \text{ GHz}/(\text{mA})^{0.5}$ due to compromise between the effective volume of resonator, current crowding suppression and total resistance
- The VCSEL with 5 mm diameter oxide aperture has a threshold current of 0.7 mA, a threshold voltage of 1.7V and a maximum output power of 7mW. 0.36W/A slope efficiency at 6mA and 29% differential quantum efficiency were achieved at room temperature. A maximum 3dB modulation frequency at a bias current of 10mA reached 10 GHz.

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